

Notice of References Cited	Application/Control No. 10/595,439		Applicant(s)/Patent Under Reexamination WOON ET AL.	
	Examiner CATHERINE THIAW		Art Unit 2493	Page 1 of 1

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*	B	US-2009/0006840	01-2009	Birger et al.	713/151
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NON-PATENT DOCUMENTS

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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.